Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/506,302	ISHIHARA ET AL.	
Examiner	Art Unit	
Nguyen N. Hanh	2834	

SEARCHED			
Class	Subclass	Date	Examiner
310	261	10/17/2006	ни
310	216	10/17/2006	HN
310	217	10/17/2006	HN
310	218	10/17/2006	HN
undate	ALL	4/7/07	HN
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TAI	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
310	261	5/6/07	HN		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
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